

**Advanced technical education in the age of cyber physical systems**

Vierhaus, Heinrich Theodor; Schölzel, Mario; **Raik, Jaan; Ubar, Raimund-Johannes** 10th European Workshop on Microelectronics Education : EWME 2014 : May 14-16, 2014, Tallinn, Estonia 2014 / p. 193-198 : ill

**High-level modeling and testing of multiple control faults in digital systems**

**Jasnetski, Artjom; Oyeniran, Adeboye Stephen; Tšertov, Anton; Schölzel, Mario; Ubar, Raimund-Johannes** Formal proceedings of the 2016 IEEE 19th International Symposium on Design and Diagnostics of Electronic Circuits & Systems (DDECS) : April 20-22, 2016, Košice, Slovakia 2016 / [6] p. : ill <http://dx.doi.org/10.1109/DDECS.2016.7482445>

**Multiple fault testing in systems-on-chip with high-level decision diagrams**

**Ubar, Raimund-Johannes; Oyeniran, Adeboye Stephen; Schölzel, Mario; Vierhaus, Heinrich Theodor** Proceedings of 2015 10th International Design & Test Symposium (IDT) : Dead Sea, Jordan, 14-16 December 2015 2015 / p. 66-71 : ill  
<http://dx.doi.org/10.1109/IDT.2015.7396738>